

Joint ICTP-IAEA Advanced Workshop on High Sensitivity 2D & 3D  
Characterisation and Imaging with Ion Beams | (smr 2856)

Contribution ID : 27

Type : **not specified**

## **Welcome and overview of Synchrotron-based analytical techniques and Elettra**

*Wednesday, 28 September 2016 14:00 (1:00)*

**Content**

**Summary**

**Presenter(s) :** GREGORATTI, Luca (Elettra Sincrotrone Trieste)

**Session Classification :** DAY 3